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Davis et al.

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FRACTIONAL INDICIA ON MEASURING **IMPLEMENTS**

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(**) Term: 14 Years

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Related U.S. Application Data

(63)Continuation-in-part of application No. 29/092,852, filed on Aug. 27, 1998, which is a continuation-in-part of application No. 29/060,518, filed on Sep. 30, 1996, now Pat. No. Des. 397,626.

(51)

U.S. Cl. **D10/74**; D10/71 (52)

(58)

References Cited (56)

U.S. PATENT DOCUMENTS

D. 398,868	*	9/1998	Taylor	D10/65
1,602,490		10/1926	Homan .	
1,776,245		9/1930	Barrett.	
2,077,828		4/1937	Dombrowski .	

3,863,348	2/1975	Herbst .
4,547,969	10/1985	Haack .
4,811,489	3/1989	Jones, Jr
5,335,421	8/1994	Walker .
5 501 019	3/1996	Concari et al

^{*} cited by examiner

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(57)**CLAIM**

The ornamental design for fractional indicia on measuring implements, as shown.

DESCRIPTION

The characteristic feature of our invention resides in the representation of the fractions on a measuring implement and their arrangements relative to their associated fractional line markers.

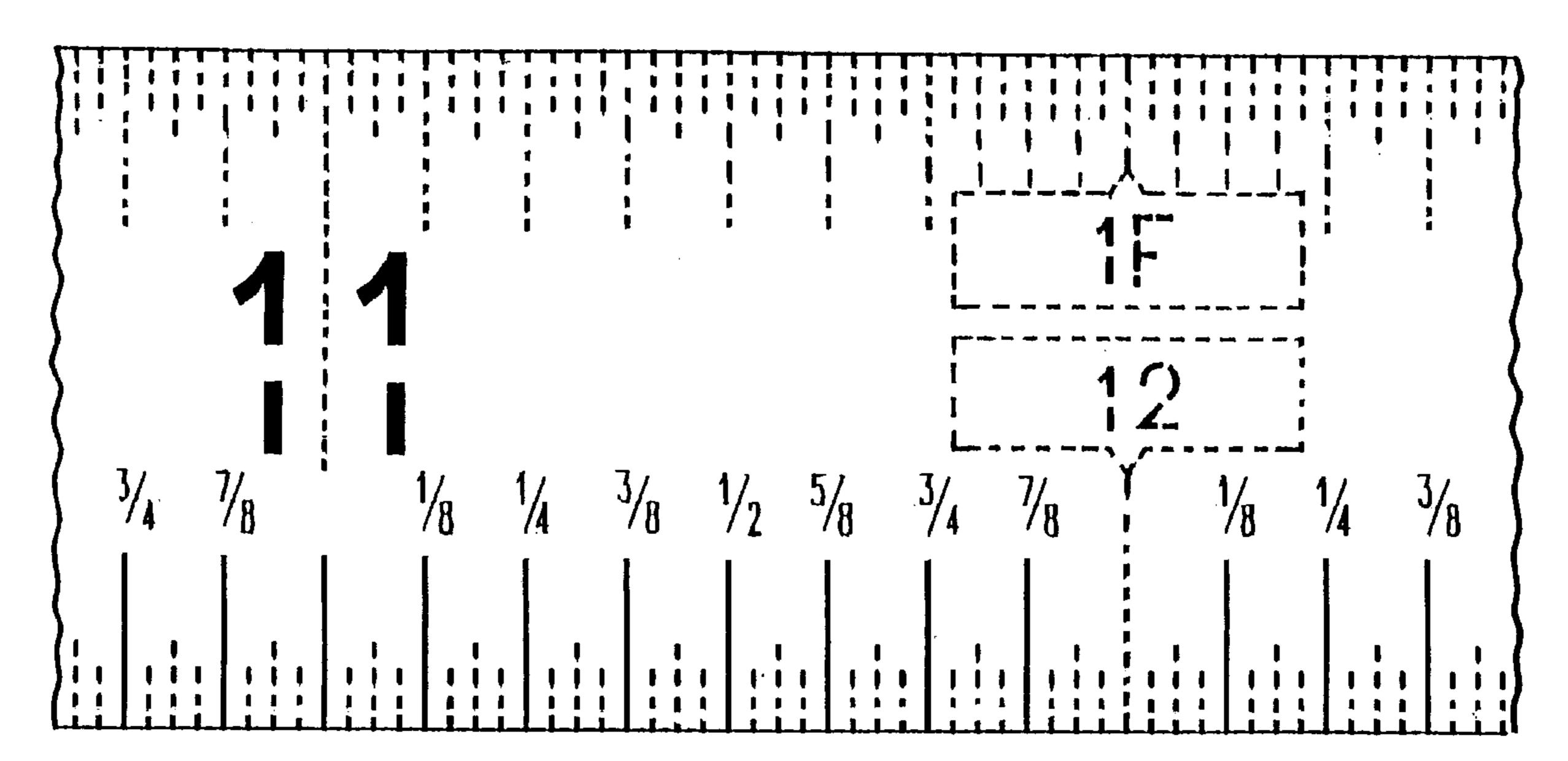
FIG. 1 is a top plan view of a measuring implement in the form of a flat tape showing our design;

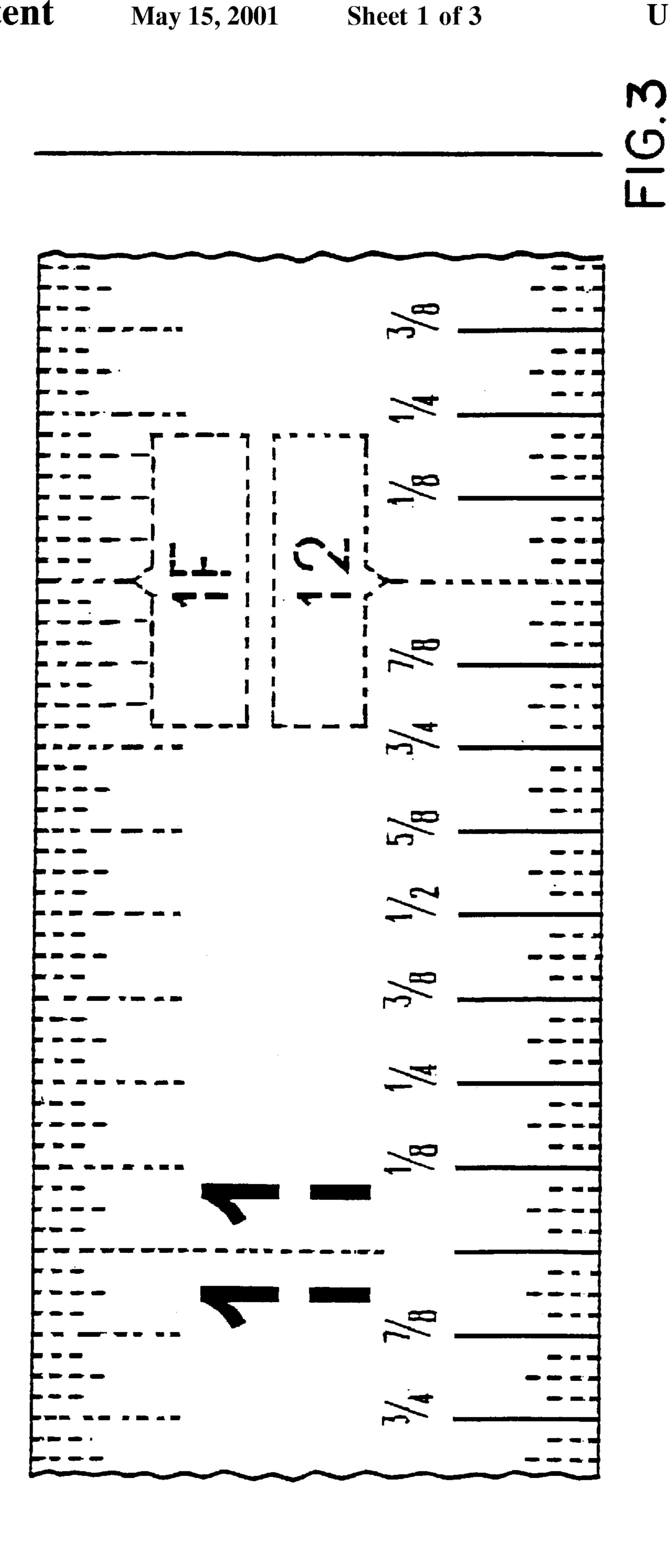
FIG. 2 is a front elevational view of the implement shown in FIG. 1, the rear elevational view being identical;

FIG. 3 is a left side elevational view of the implement shown in FIG. 1, the right side elevational view being identical; FIG. 4 is a top plan view of an alternate embodiment of our design; and,

FIG. 5 is a top plan view of yet another alternate embodiment of our design.

1 Claim, 3 Drawing Sheets





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